

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10563723	YUAN ET AL.
Examiner	Art Unit	
M. Lee	2622	

SEARCHED

Class	Subclass	Date	Examiner
348	744, 552, 441,	9/10/08	ml
345	1.1, 204	9/10/08	ml

SEARCH NOTES

Search Notes	Date	Examiner
east	9/10/08	ml

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/M. Lee/ Primary Examiner, Art Unit 2622
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